Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/509,074	CHEN ET AL.	
Examiner	Art Unit	
Sahiha Oazi	1616	

	SEARCHED			
Class	Subclass	Date	Examiner	
548	453	9/27/2006		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH I (INCLUDING SEAR)
	DATE	EXMR
STN DATABASE SEARCH	9/27/2006	STIC
REGISTRY		
STRUCTURE		
HCAPLUS		
INVENTOR SEARCH		